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1 **Effects of noise dither signals on differential linearity and effective resolution of sigma-delta A/D converters in measuring applications**
Badzmirowski, K.; Jackiewicz, B.;
Instrumentation and Measurement Technology Conference, 1998. IMTC/98. Conference Proceedings. IEEE , Volume: 2 , 18-21 May 1998
Pages:1229 - 1232 vol.2

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